## **Ordering Options**

SO-5 Package	Standard DIP	SO-8 Package
HCPL-M452	HCPL-4502	HCPL-0452
HCPL-M453	HCPL-4503	HCPL-0453

NOTE: These devices equivalent to 6N135/6N136 devices but without the base lead.

## **Ordering Information**

HCPL-M452 and HCPL-M453 are UL Recognized with 3750 Vrms for 1 minute per UL1577.

Option							
Part Number	non-RoHS RoHS Compliant		Package	Surface Mount	Tape and Reel	Quantity	
HCPL-M452	-000E	No option	SO-5	Х		100 per tube	
HCPL-M453	-500E	#500		X	X	1500 per tube	

To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry.

#### Example 1:

HCPL-M452-500E to order product of SO-5 surface mount package in tape and reel packaging and RoHS compliant.

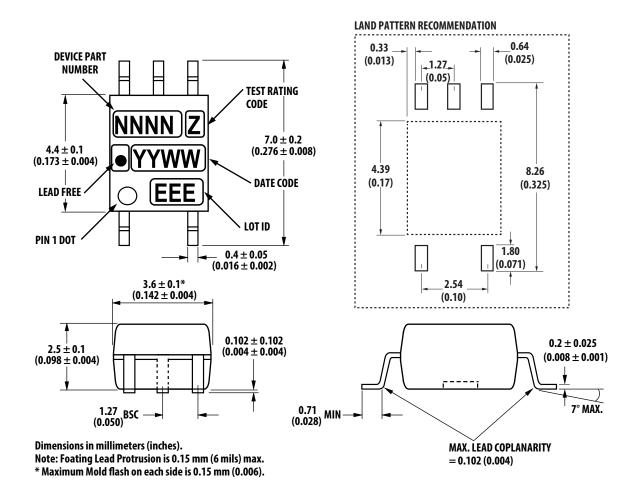
#### Example 2:

HCPL-M452 to order product of SO-5 surface mount package in tube packaging and non-RoHS compliant.

Option data sheets are available. Contact your Broadcom sales representative or authorized distributor for information

**NOTE:** The notation '#XXX' is used for existing products, while (new) products launched since July 15, 2001 and RoHS compliant will use '-XXXE.

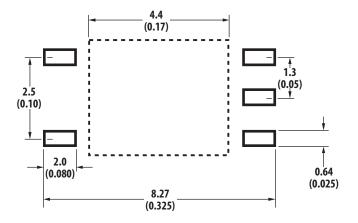
# **Outline Drawing (JEDEC MO-155)**



#### **Schematic**

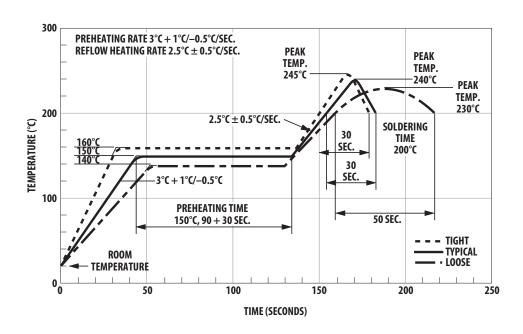
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#### **Land Pattern Recommendation**



Dimensions in millimeters and (in.).

#### **Solder Reflow Thermal Profile**



NOTE: Note: Non-halide flux should be used.

#### **Recommended Pb-Free IR Profile**

The recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision).

Non-halide flux should be used.

## **Regulatory Information**

The HCPL-M452/M453 are approved by the following organizations:

	Approved under UL 1577, component recognition program up to $V_{ISO}$ = 3750 $V_{RMS}$ expected prior to product release.
CSA	Approved under CSA Component Acceptance Notice #5.

# **Insulation Related Specifications**

Parameter	Symbol	Value	Units	Conditions
Min External Air Gap (Clearance)	L(IO1)	≥ 5	mm	Measured from input terminals to output terminals
Min. External Tracking Path (Creepage)	L(IO2)	≥ 5	mm	Measured from input terminals to output terminals
Min. Internal Plastic Gap (Clearance)		0.08	mm	Through insulation distance conductor to conductor
Tracking Resistance	CTI	175	V	DIN IEC 112/VDE 0303 Part 1
Isolation Group (per DIN VDE 0109)		Illa		Material Group DIN VDE 0109

# **Absolute Maximum Ratings**

No derating required up to 85°C.

Storage Temperature	–55°C to +125°C
Operating Temperature	–55°C to +100°C
Average Input Current – I <sub>F</sub>	25 mA <sup>a</sup>
Peak Input Current – I <sub>F</sub>	50 mA <sup>b</sup> (50% duty cycle, 1 ms pulse width)
Peak Transient Input Current – I <sub>F</sub>	1.0A (1 µs pulse width, 300 pps)
Reverse Input Voltage – V <sub>R</sub> (Pin3-1)	5V
Input Power Dissipation	45 mW <sup>c</sup>
Average Output Current – I <sub>O</sub> (Pin 5)	8 mA
Peak Output Current	16 mA
Output Voltage – V <sub>O</sub> (Pin 5-4)	-0.5V to 20V
Supply Voltage – V <sub>CC</sub> (Pin 6-4)	-0.5V to 30V
Output Power Dissipation	100 mW <sup>d</sup>
Infrared and Vapor Phase Reflow Temperature	See below

- a. Derate linearly above 85°C free-air temperature at a rate of 0.5 mA/°C.
- b. Derate linearly above 85°C free-air temperature at a rate of 1.0 mA/°C.
- c. Derate linearly above 85°C free-air temperature at a rate of 1.1 mW/°C.
- d. Derate linearly above 85°C free-air temperature at a rate of 2.3 mW/°C.

# **Electrical Specifications**

Over recommended temperature ( $T_A = 0$ °C to 70°C) unless otherwise specified.

NOTE: Use of a 0.1-µF bypass capacitor connected between pins 4 and 6 is recommended.

Parameter	Symbol	Min.	Typ.a	Max.	Units	Test Conditions			Figure	Note
Current Transfer Ratio	CTR	20	24	50	%	T <sub>A</sub> = 25°C	V <sub>O</sub> = 0.4V	V <sub>CC</sub> = 4.5V	1, 2, 4	b
		15	25	_			V <sub>O</sub> = 0.5V	I <sub>F</sub> = 16 mA		
Logic Low Output Voltage	V <sub>OL</sub>	_	0.1	0.4	V	T <sub>A</sub> = 25°C	I <sub>O</sub> = 3.0 mA			
		_	_	0.5			I <sub>O</sub> = 2.4 mA			
Logic High Output Current	I <sub>OH</sub>	_	0.003	0.5	μΑ	T <sub>A</sub> = 25°C	$V_O = V_{CC} =$ 5.5V	I <sub>F</sub> = 0 mA	7	
		_	0.01	1.0	_	T <sub>A</sub> = 25°C	$V_O = V_{CC} = 5.5V$			
		_	_	50						
Logic Low Supply Current	I <sub>CCL</sub>	_	50	200		I <sub>F</sub> = 16 mA	V <sub>o</sub> = Open	V <sub>CC</sub> = 15V		С
Logic High Supply Current	I <sub>CCH</sub>	_	0.02	1		T <sub>A</sub> = 25°C	I <sub>F</sub> = 0 mA	V <sub>CC</sub> = 15V		С
		_	0.02	2			V <sub>O</sub> = open			
Input Forward Voltage	V <sub>F</sub>	_	1.5	1.7	V	T <sub>A</sub> = 25°C	I <sub>F</sub> = 16 mA		3	
		_	1.5	1.8						
Input Reverse Breakdown Current	BV <sub>R</sub>	5	_		V	I <sub>R</sub> = 10 μA				
Temperature Coefficient of Forward Voltage	$\Delta V_F / \Delta T_A$	_	-1.6		mV/°C	I <sub>F</sub> = 16 mA				
Input Capacitance	C <sub>IN</sub>	_	60	_	pF	f = 1 MHz	V <sub>F</sub> = 0V			
Input-Output Insulation	V <sub>ISO</sub>	3750	_	_	$V_{RMS}$		RH < 50%	t = 1 min		d <sub>,</sub> e
Voltage							$T_A = 25^{\circ}C$			
Resistance (Input-Output)	R <sub>I-O</sub>		10 <sup>12</sup>		Ω	V <sub>I-O</sub> = 500 Vdc				d
Capacitance (Input-Output)	C <sub>I-O</sub>	_	0.6		pF	f = 1 MHz				d

- a. All typicals at  $T_A = 25$ °C.
- $b. \ \ CURRENT\ TRANSFER\ RATIO\ in\ percent\ is\ defined\ as\ the\ ratio\ of\ output\ collector\ current,\ I_O,\ to\ the\ forward\ LED\ input\ current,\ I_F,\ times\ 100.$
- c. Use of a 0.1-µF bypass capacitor connected between pins 4 and 6 is recommended.
- d. Device considered a two-terminal device: Pins 1 and 3 shorted together and Pins 4, 5 and 6 shorted together.
- e. In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage ≥ 4500 V<sub>RMS</sub> for 1 second (leakage detection current limit, I<sub>i-e</sub> ≤ 5 µA).

# **Switching Specifications**

Over recommended temperature ( $T_A = 0$ °C to 70°C)  $V_{CC} = 5V$ ,  $I_F = 16$  mA unless otherwise specified.

Parameter	Symbol	Device	Min.	Typ. <sup>a</sup>	Max.	Units		Test Conditions			Note
Propagation Delay Time to Logic Low at	t <sub>PHL</sub>			0.2	0.8 1.0	μs	T <sub>A</sub> = 25°C	R <sub>I</sub> = 1.9kΩ		5., 6, 10	b
Output Propagation	t <sub>PLH</sub>		_	0.6	0.8	-	T <sub>A</sub> = 25°C	$R_{l} = 1.9k\Omega$		5, 6, 10	b
Delay Time to Logic High at Output			_	0.6	1.0						
Common  CM <sub>H</sub>   Mode Transient Immunity at Logic High Level Output		HCPL- M452	_	1	_	kV/μs		V <sub>CM</sub> = 10 V <sub>P-P</sub>	I <sub>F</sub> = 0 mA T <sub>A</sub> = 25°C	11	b, c
		HCPL- M453	15	30	_			V <sub>CM</sub> = 1500 V <sub>P-P</sub>	$R_L = 1.9 \text{ k}\Omega$		
Common  CM <sub>L</sub>	CM <sub>L</sub>	HCPL- M452	_	1	_	-		V <sub>CM</sub> = 10 V <sub>P-P</sub>	I <sub>F</sub> = 16 mA T <sub>A</sub> = 25°C	11	b, c
Transient Immunity at Logic Low Level Output	inity at M433	T <sub>A</sub> = 25°C	V <sub>CM</sub> = 1500 V <sub>P-P</sub>	$R_L = 1.9 \text{ k}\Omega$							
Bandwidth	BW		_	3	_	MHz		$R_L$ = 100 kΩ See Test Circuit		8, 9	d

- a. All typicals at  $T_A = 25$ °C.
- b. The 1.9 k $\Omega$  load represents 1 TTL unit load of 1.6 mA and the 5.6 k $\Omega$  pull-up resistor.
- c. Common transient immunity in a Logic High level is the maximum tolerable (positive)  $dV_{CM}/dt$  on the rising edge of the common mode pulse,  $V_{CM}$ , to assure that the output will remain in a Logic High state (that is,  $V_O > 2.0V$ ). Common mode transient immunity in a Logic Low level is the maximum tolerable (negative)  $dV_{CM}/dt$  on the falling edge of the common mode pulse signal, VCM to assure that the output will remain in a Logic Low state (that is,  $V_O < 0.8V$ ).
- d. The frequency at which the ac output voltage is 3 dB below its mid-frequency value.

Figure 1: dc and Pulsed Transfer Characteristics

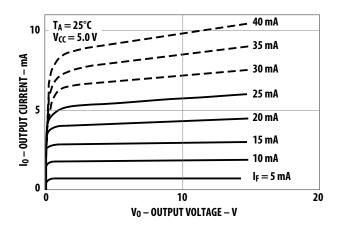


Figure 3: Input Current vs. Forward Voltage

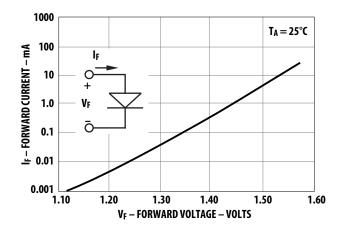


Figure 5: Propagation Delay vs. Temperature

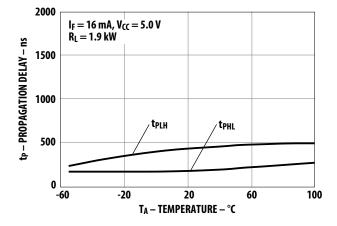


Figure 2: Current Transfer Ratio vs. Input Current

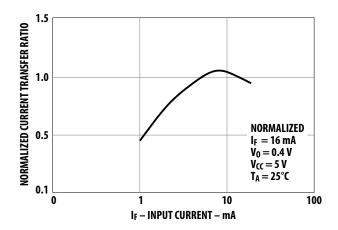


Figure 4: Current Transfer Ratio vs. Temperature

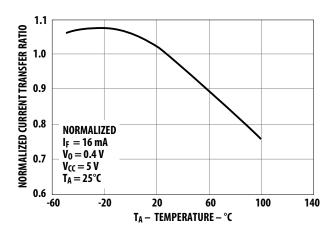


Figure 6: Propagation Delay Time vs. Load Resistance

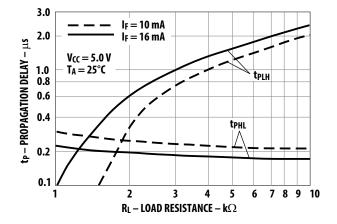


Figure 7: Logic High Output Current vs. Temperature

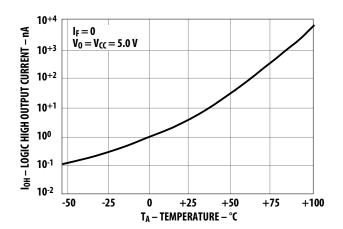


Figure 8: Small-Signal Current Transfer Ratio vs. Quiescent Input Current

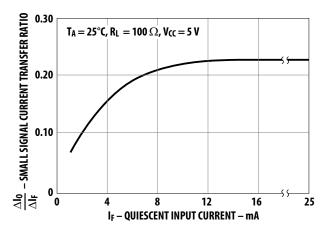
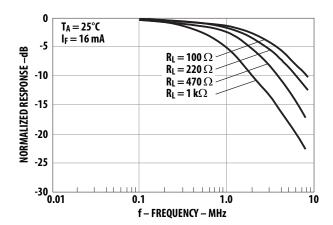
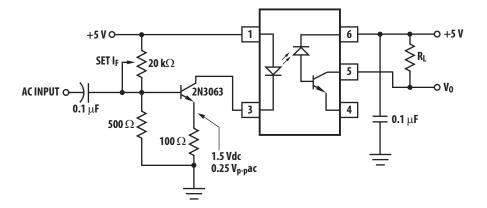


Figure 9: Frequency Response





#### Figure 10: Switching Test Circuit

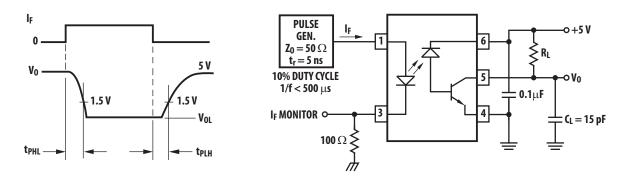
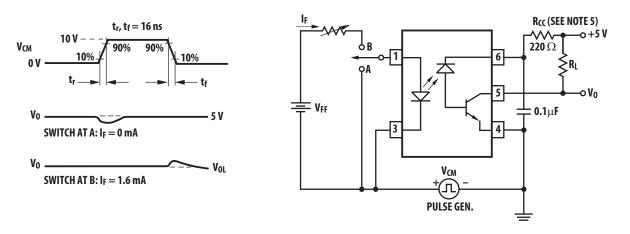


Figure 11: Test Circuit for Transient Immunity and Typical Waveforms



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